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Paper Title : M-Lens An IoT based Deep Learning Device

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Introduction

- Aim of an inspection is to reduce number of defects.
- Current inspection techniques are expensive and inspection devices are specialized.
- Such device and technique fails in dynamic environment where novel defects are the norm
- M-Lens is a hand-held device that automatically classifies defective parts even if the defects are novel and previously uncategorized.

Objectives

- The objective of this paper is to show the designing, development and working capabilities of such a generic hand-held device.
- The features, technical specification and user interface of the device are specified.
- Transfer learning technique is used for time optimization.

Existing System

- Portable object detection devices:
 - AWS DeepLens - Not user friendly, on-machine inference, portable but heavy, no on-screen display.
 - Google Glass - Custom detection is not possible.
- Real-time portable training
 - Intel Movidius - Real-time inference is not possible.

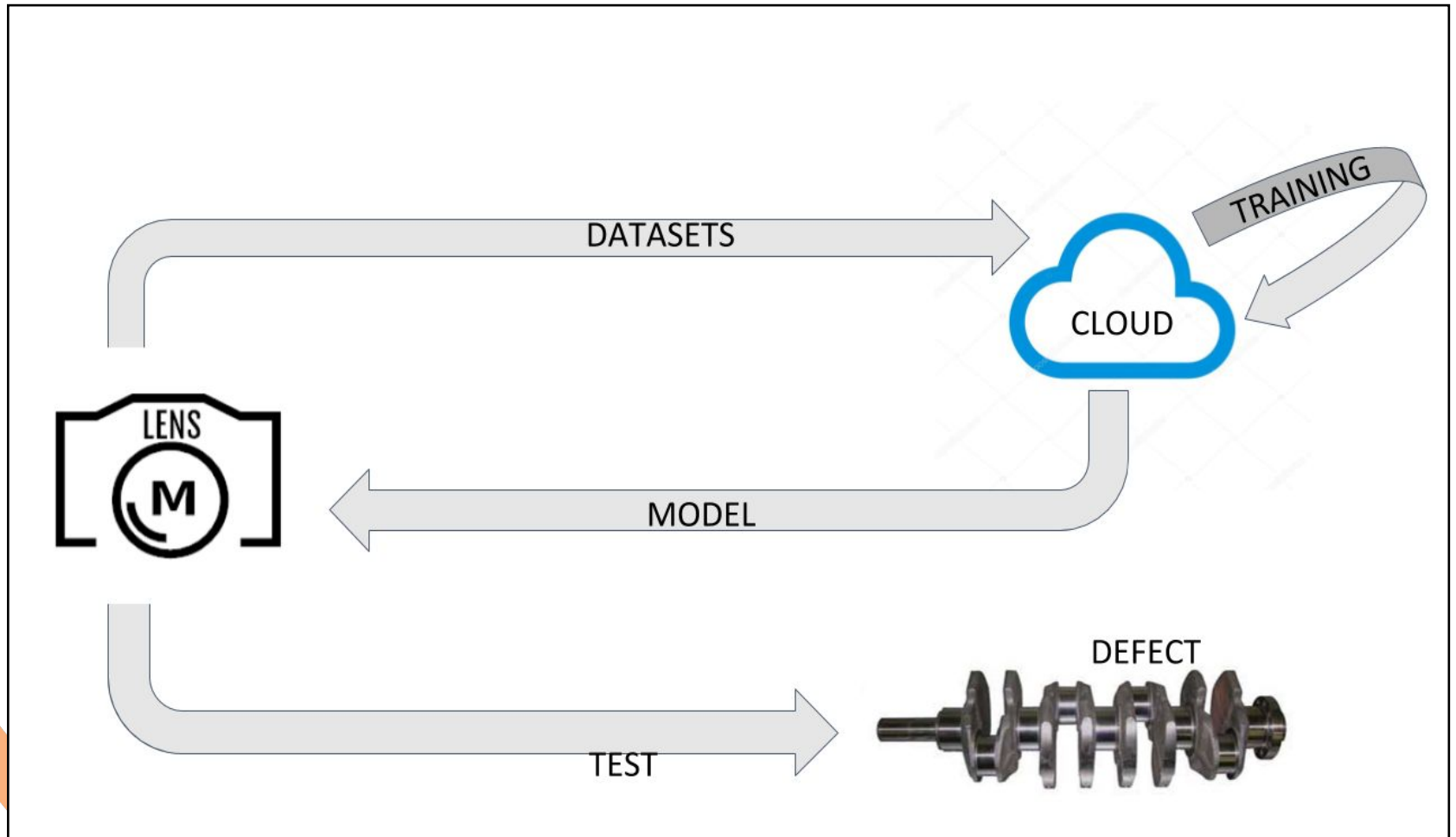
Proposed System

- Architecture considered were edge and server-side computing. Servers-side computing was selected based on the speed consideration.
- Hardware considered were Arduino, Raspberry-Pi and FPGA. Raspberry-Pi was selected based on the cost.
- DNN considered were AlexNet, MobileNet and GoogleNet. MobileNet was selected based on Accuracy to MAC operations ratio.

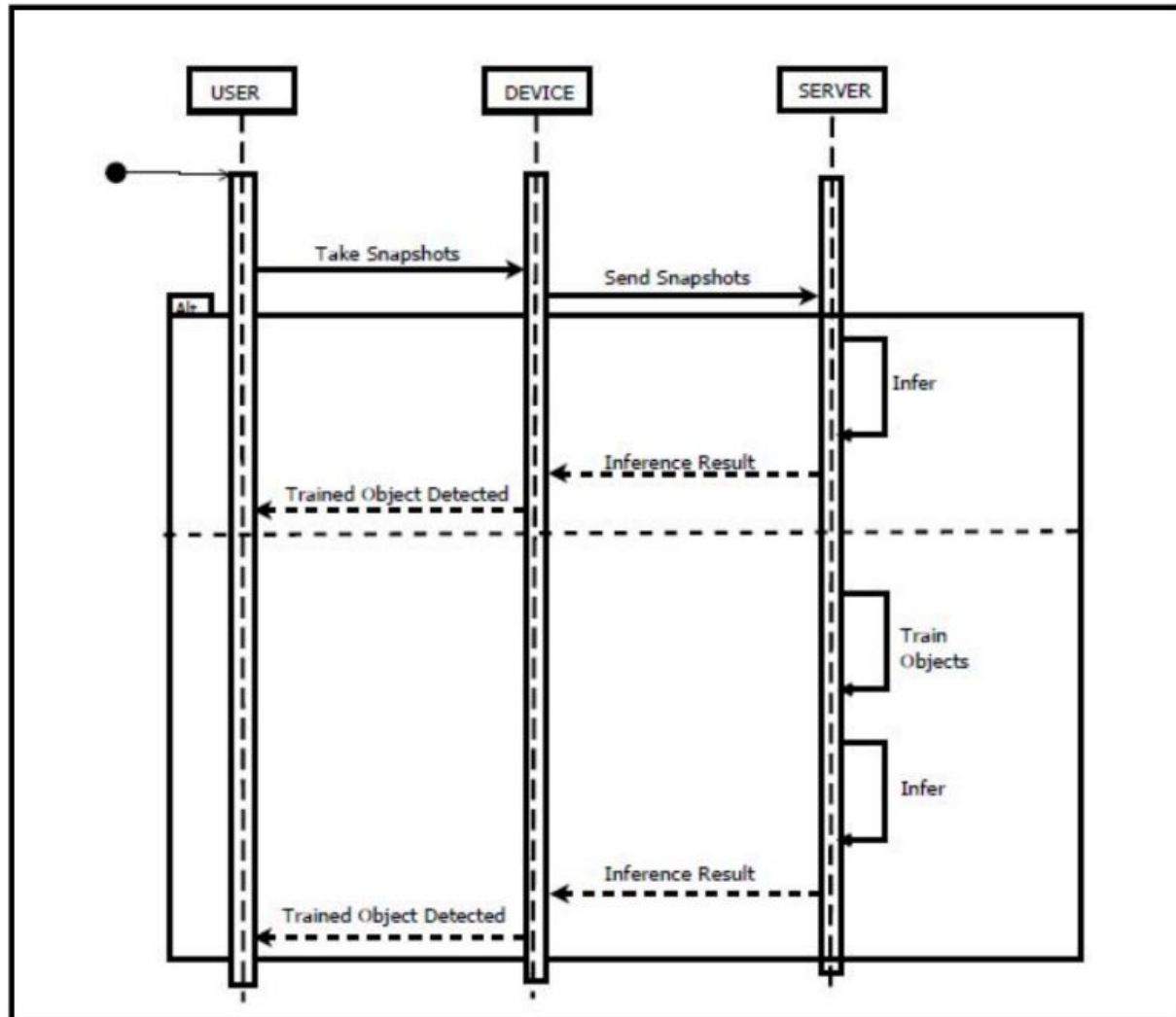
Features

- Cloud training
- Portable
- Transfer Learning
- Training Custom Defect

Architecture



Implementation



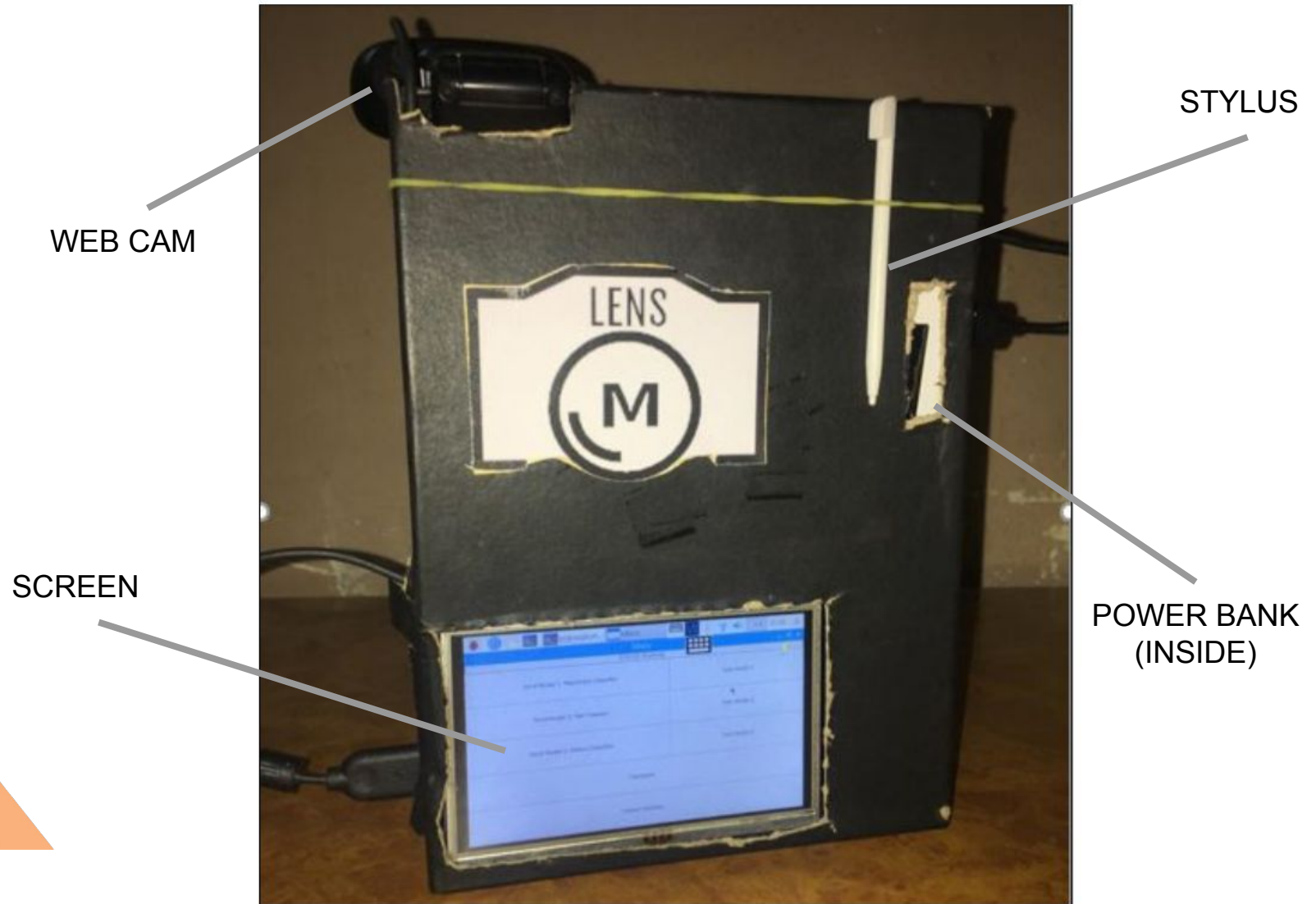
Working

- Input
 - Image resolution and processing time are directly proportional.
- Training
 - Transfer Learning
 - MobileNet for Transfer Learning
 - Training custom data
 - User Input Data
 - Classifiers
 - Industry requirement specific

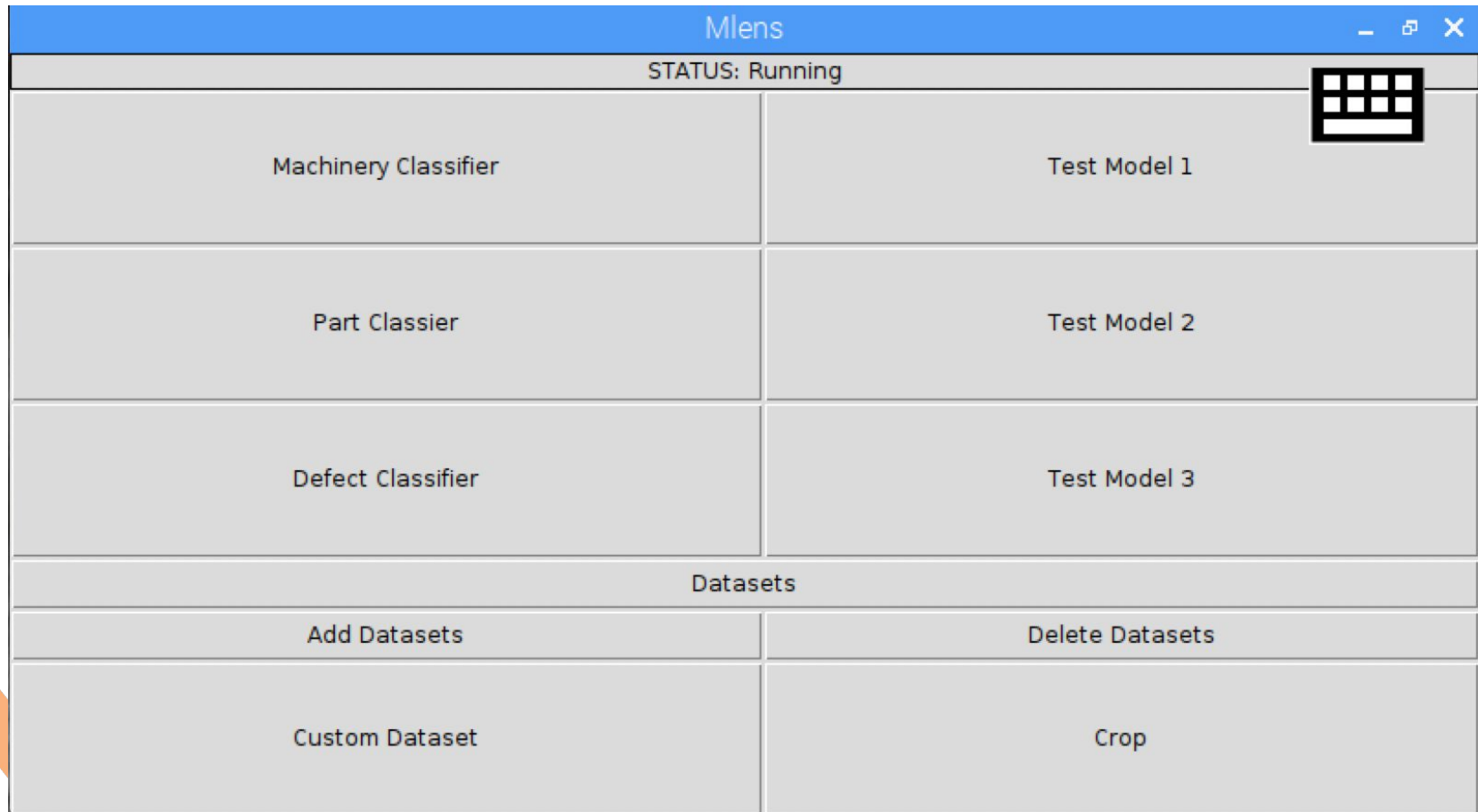
Working

- Inference
 - Real-time defect detection
- Communication
 - AWS Cloud computing
- GUI
 - Datasets
 - Custom dataset
 - Retrieve Model
 - Test Model

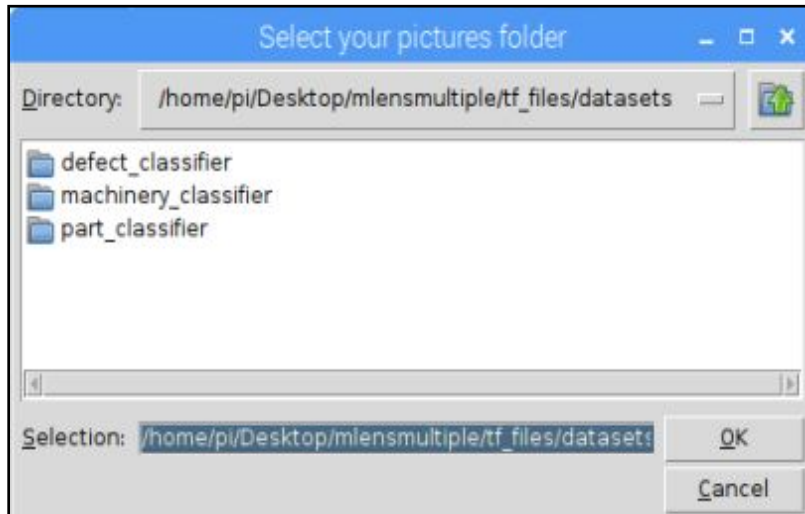
M-LENS



GUI



GUI

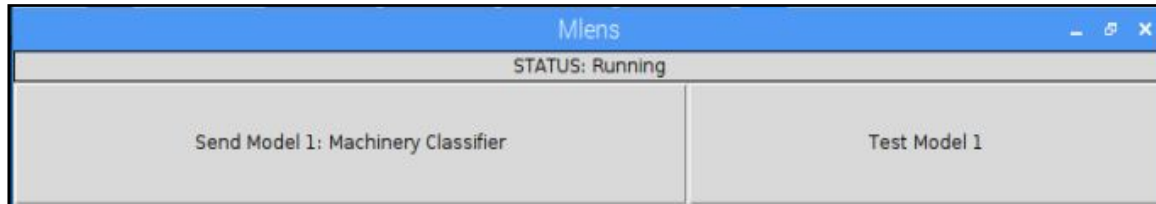


Datasets: Shown are all the datasets present on the device along with image storage directory information.

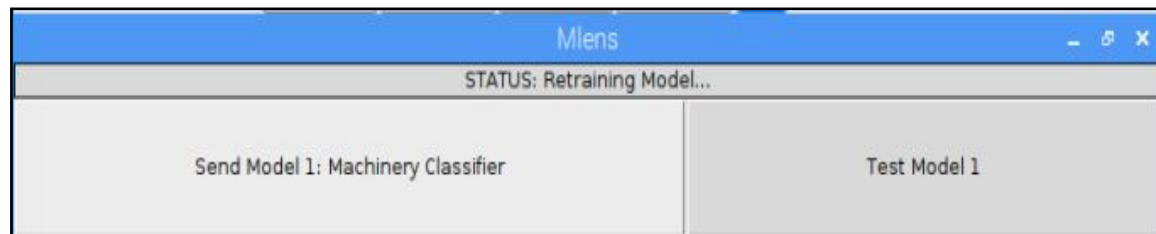
Custom Dataset: The snapshot button clicks 30 images (from multiple angles).



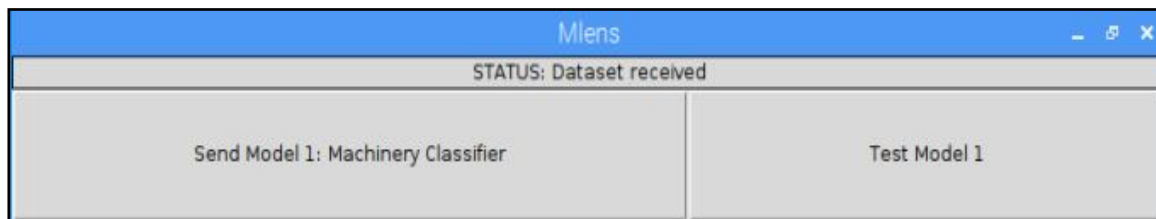
GUI



Running: The process of sending dataset to the server is going on.



Retraining Model: The server is retraining the model and sends the updated model to the device.



Datasets Received: The server has received the datasets.

GUI



Test Model: After receiving the updated model, inference takes place. The result shows whether the image is faulty or not. It also displays the type of fault detected.

Applications

- Crops - Plant fungus, bacteria and other blight detection
- Pipes damage inspection
- Scrap processing plants' maintenance.
- Part manufacturing industry
- Aircraft and Shipbuilding industry

Conclusion

- Broad scope of application makes it viable to tackle variety of issues from industrial manufacturing to ship and aircraft building.
- M-Lens uses supervised learning where the user specifies the class name. This results in fast and efficient way of detecting and classifying defects while minimizing human intervention.
- Using transfer learning the device develops its knowledge about the defects in the cloud.



Video Link -

<https://www.youtube.com/watch?v=2ZT-dtsKMFM>



Q&A